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(12) **United States Design Patent** (10) **Patent No.:** **US D554,008 S**
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(54) **PROBE HANDLE FOR THERMOMETER**

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(**) Term: **14 Years**

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Related U.S. Application Data

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(51) **LOC (8) Cl.** **10-04**

(52) **U.S. Cl.** **D10/60**

(58) **Field of Classification Search** D10/57, D10/60; 374/100-209; D8/307-308
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe handle for thermometer, as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of a probe handle for thermometer with parts of a thermometer probe other than the probe handle shown in phantom;

FIG. 2 is a front elevational view thereof;

FIG. 3 is a rear elevational view thereof.

FIG. 4 is a left side elevational view thereof.

FIG. 5 is a right side elevational view thereof.

FIG. 6 is a top plan view thereof;

FIG. 7 is a bottom plan view thereof; and,

FIG. 8 is a rear perspective view of the probe handle in combination with the probe.

Portions of the views shown in phantom form no part of the design.

1 Claim, 7 Drawing Sheets

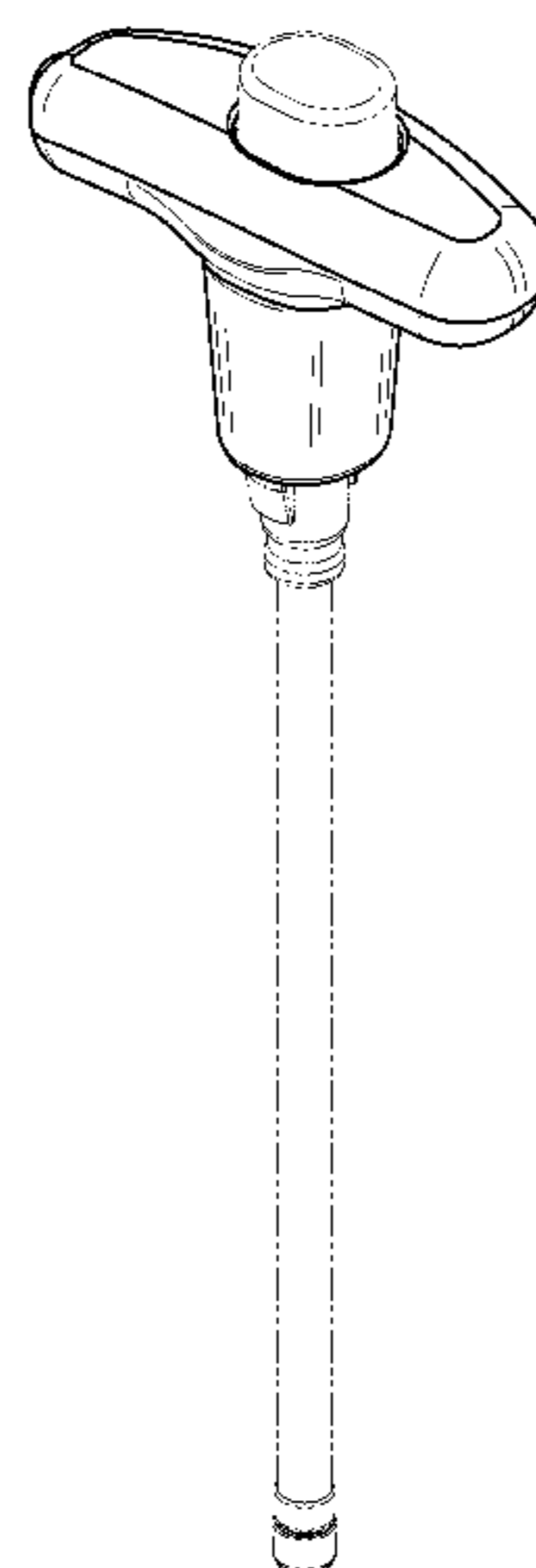


FIG. 1

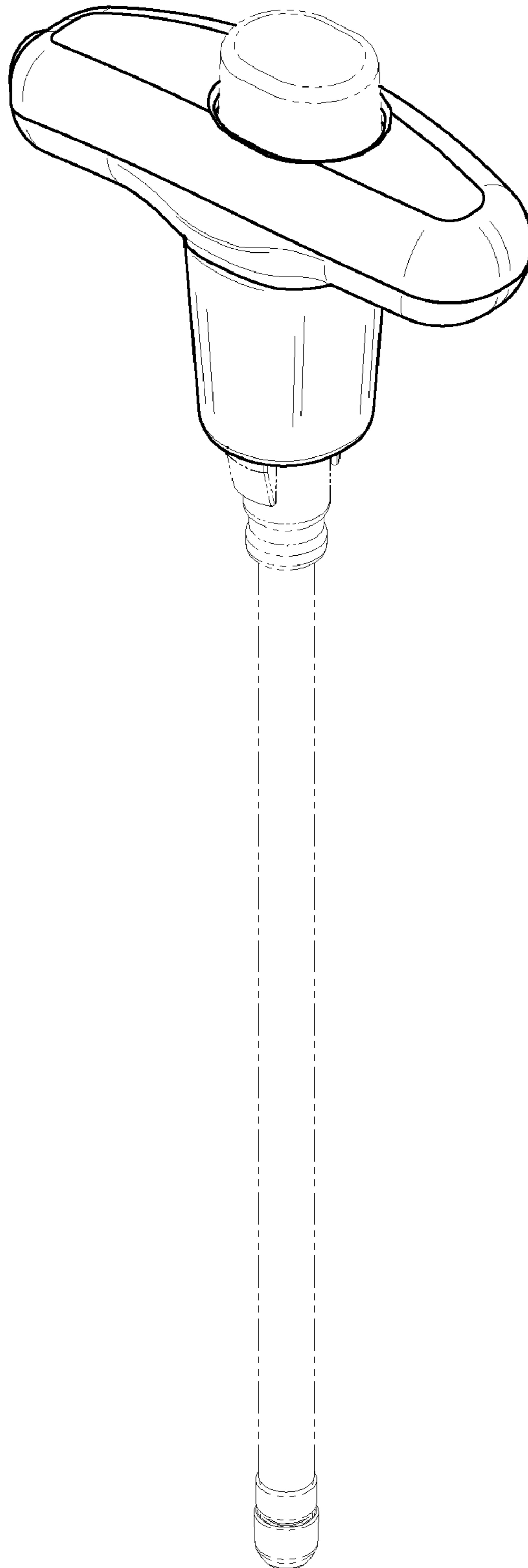


FIG. 2

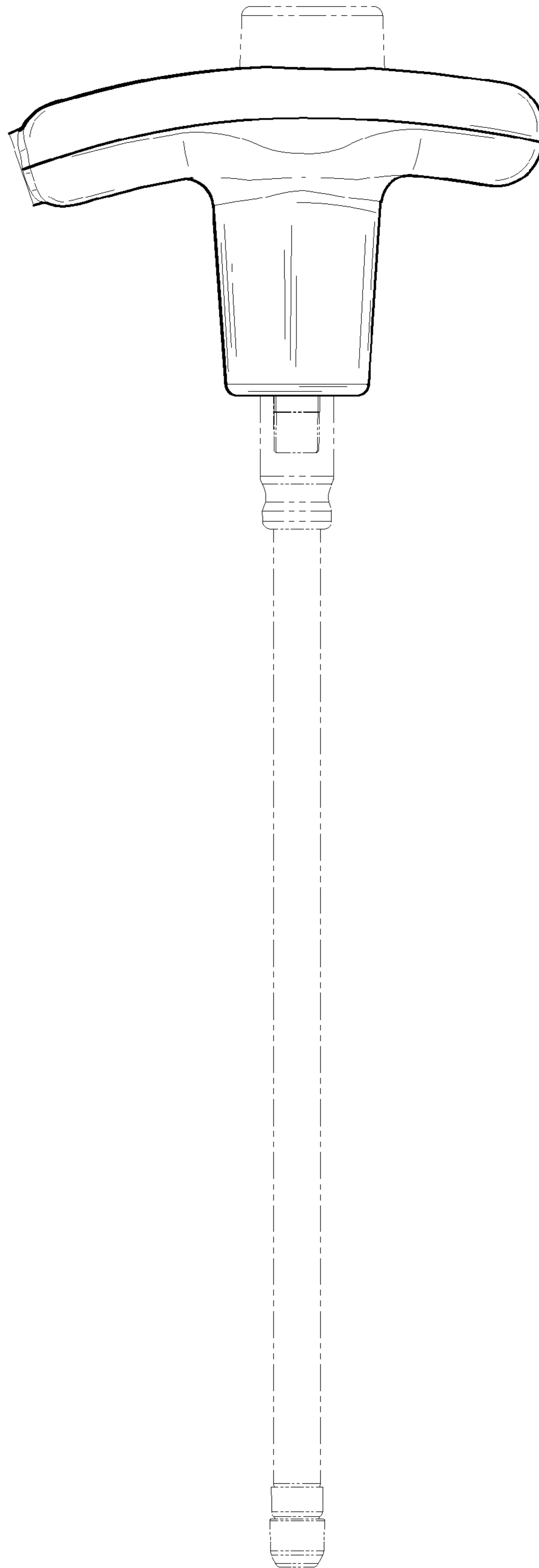


FIG. 3

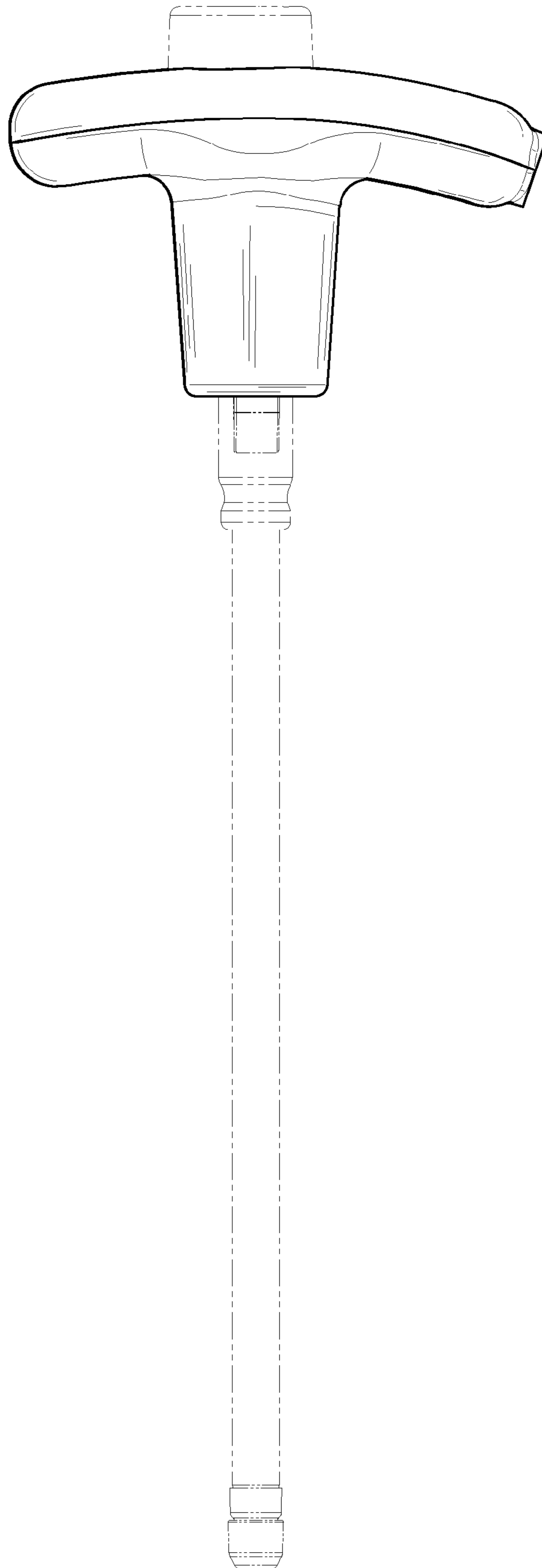


FIG. 4

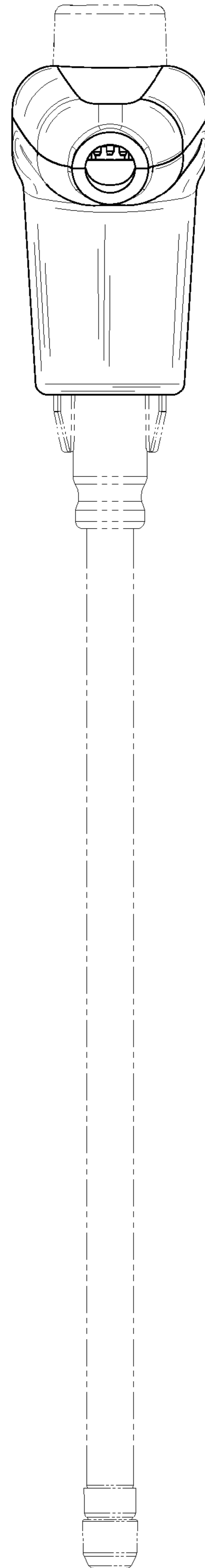


FIG. 5

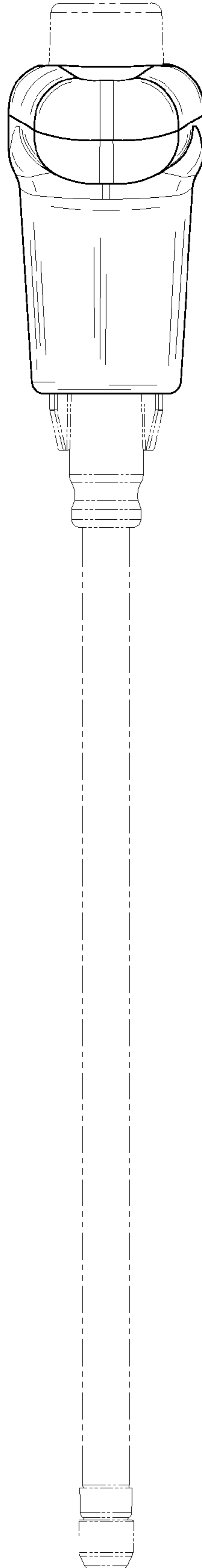


FIG. 6

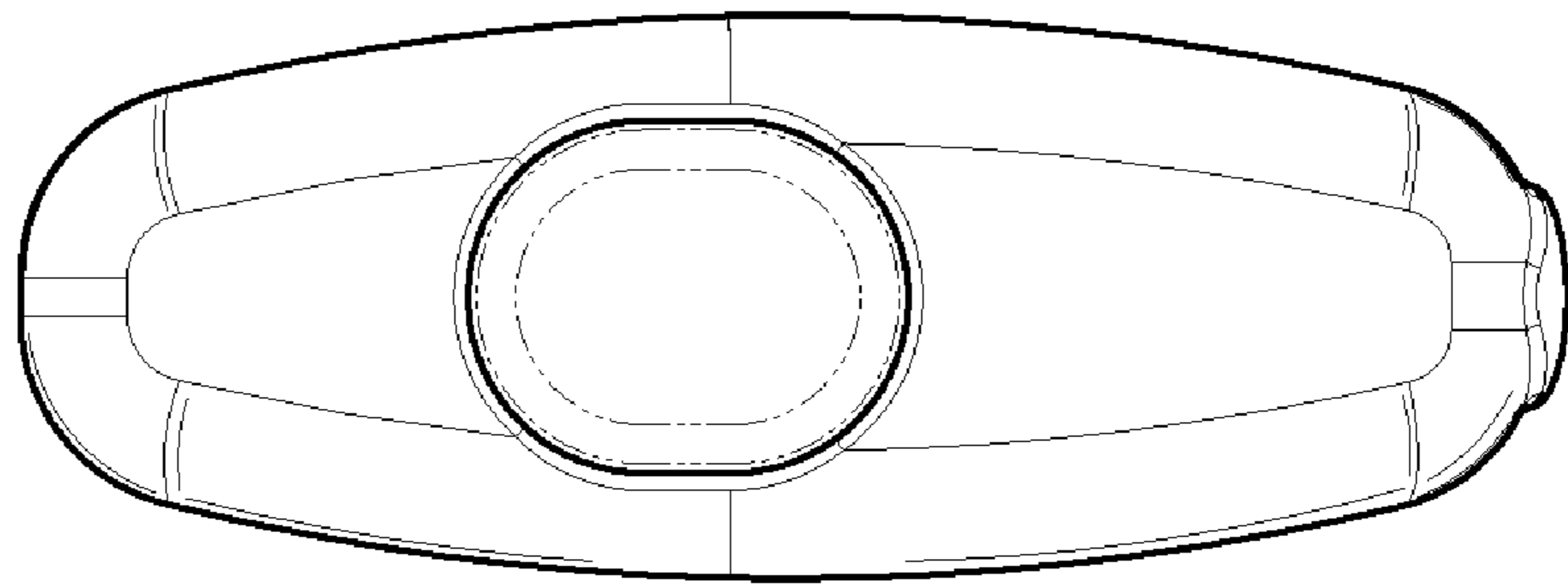


FIG. 7

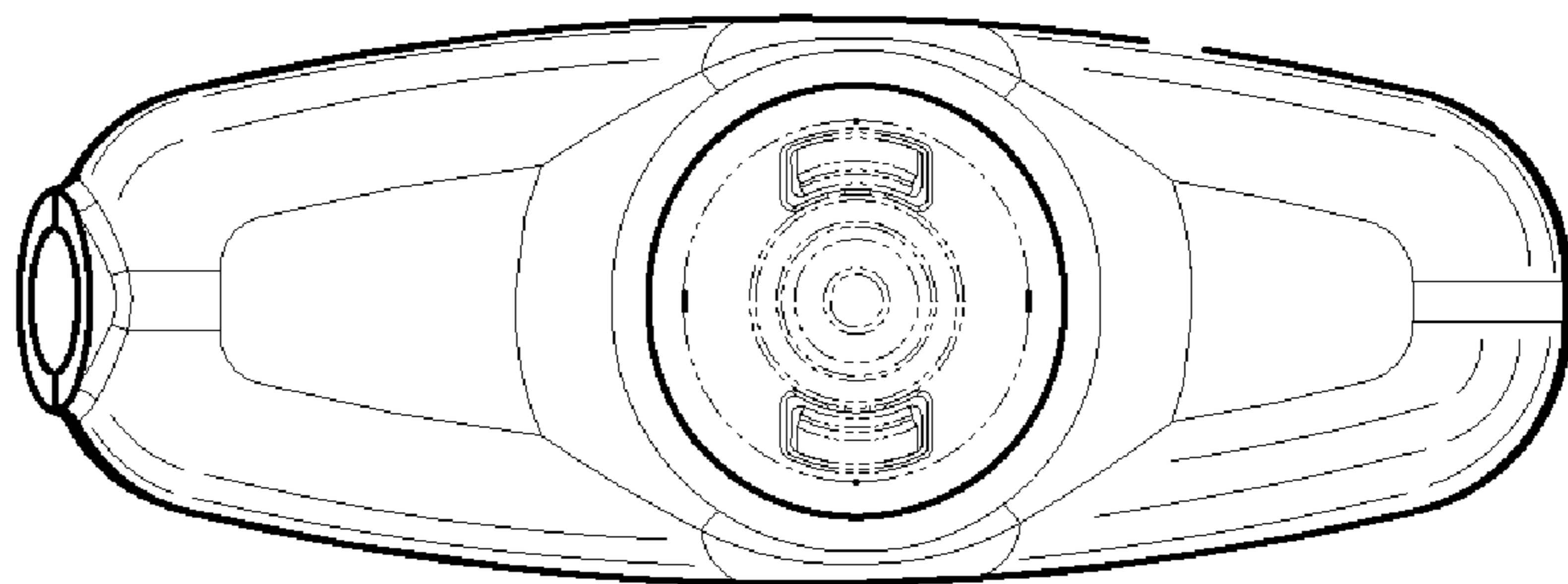


FIG. 8

